



Erratum

Erratum to “An algorithm for calculating the lower confidence bounds of C_{PU} and C_{PL} with application to low-drop-out linear regulators”

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The authors regret that in the above article the comparison given in Table 4 was meaningless. The entries of the first row were obtained using the uniformly minimum variance unbiased estimator (UMVUE) \tilde{C}_{PU} for $\tilde{C}_{PU} = 0.7(0.1)1.5$, while the entries of the second row were taken directly from [1], as obtained by using the biased estimator \hat{C}_{PU} under $\hat{C}_{PU} = 0.7(0.1)1.5$. They cannot be put together in Table 4 for comparison. Consequently, the remark “our approach provides better bound (particularly for small n), which is closer to the real \tilde{C}_{PU} (or \tilde{C}_{PL}), and therefore should be recommended for real-world applications” was not correct. All the theories, derivations, results, and other tables remain unchanged.

Reference

- [1] Chou YM, Owen DB, Borrego SA. Lower confidence limits on process capability indices. *Journal of Quality Technology* 1990;22(3):223–9.

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